Intel - 5SGXEA7K2F40C2N Datasheet

Details	
Product Status	Obsolete
Number of LABs/CLBs	234720
Number of Logic Elements/Cells	622000
Total RAM Bits	51200000
Number of I/O	696
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea7k2f40c2n

Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering (1), (2), (3) **(Part 2 of 2)**

Transceiver Speed Grade	Core Speed Grade							
	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L	I3YY	I4
3 GX channel—8.5 Gbps	—	Yes	Yes	Yes	—	Yes	Yes (4)	Yes

Notes to Table 1:

(1) C = Commercial temperature grade; I = Industrial temperature grade.
(2) Lower number refers to faster speed grade.
(3) C2L, I2L, and I3L speed grades are for low-power devices.
(4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices.

Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering (1), (2)

Transceiver Speed Grade	Core Speed Grade			
	C1	C2	I2	I3
2 GX channel—12.5 Gbps GT channel—28.05 Gbps	Yes	Yes	—	—
3 GX channel—12.5 Gbps GT channel—25.78 Gbps	Yes	Yes	Yes	Yes

Notes to Table 2:

(1) C = Commercial temperature grade; I = Industrial temperature grade.
(2) Lower number refers to faster speed grade.

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

CAUTION

Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 1 of 2)

Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Power supply for core voltage and periphery circuitry	–0.5	1.35	V
V_{CCPT}	Power supply for programmable power technology	–0.5	1.8	V
V_{CCPGM}	Power supply for configuration pins	–0.5	3.9	V
V_{CC_AUX}	Auxiliary supply for the programmable power technology	–0.5	3.4	V
V_{CCBAT}	Battery back-up power supply for design security volatile key register	–0.5	3.9	V
V_{CCPD}	I/O pre-driver power supply	–0.5	3.9	V
V_{CCIO}	I/O power supply	–0.5	3.9	V

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 2 of 2)

Symbol	Description	Minimum	Maximum	Unit
V_{CCD_FPLL}	PLL digital power supply	–0.5	1.8	V
V_{CCA_FPLL}	PLL analog power supply	–0.5	3.4	V
V_I	DC input voltage	–0.5	3.8	V
T_J	Operating junction temperature	–55	125	°C
T_{STG}	Storage temperature (No bias)	–65	150	°C
I_{OUT}	DC output current per pin	–25	40	mA

Table 4 lists the absolute conditions for the transceiver power supply for Stratix V GX, GS, and GT devices.

Table 4. Transceiver Power Supply Absolute Conditions for Stratix V GX, GS, and GT Devices

Symbol	Description	Devices	Minimum	Maximum	Unit
V_{CCA_GXBL}	Transceiver channel PLL power supply (left side)	GX, GS, GT	–0.5	3.75	V
V_{CCA_GXBR}	Transceiver channel PLL power supply (right side)	GX, GS	–0.5	3.75	V
V_{CCA_GTBR}	Transceiver channel PLL power supply (right side)	GT	–0.5	3.75	V
V_{CCHIP_L}	Transceiver hard IP power supply (left side)	GX, GS, GT	–0.5	1.35	V
V_{CCHIP_R}	Transceiver hard IP power supply (right side)	GX, GS, GT	–0.5	1.35	V
V_{CCHSSI_L}	Transceiver PCS power supply (left side)	GX, GS, GT	–0.5	1.35	V
V_{CCHSSI_R}	Transceiver PCS power supply (right side)	GX, GS, GT	–0.5	1.35	V
V_{CCR_GXBL}	Receiver analog power supply (left side)	GX, GS, GT	–0.5	1.35	V
V_{CCR_GXBR}	Receiver analog power supply (right side)	GX, GS, GT	–0.5	1.35	V
V_{CCR_GTBR}	Receiver analog power supply for GT channels (right side)	GT	–0.5	1.35	V
V_{CCT_GXBL}	Transmitter analog power supply (left side)	GX, GS, GT	–0.5	1.35	V
V_{CCT_GXBR}	Transmitter analog power supply (right side)	GX, GS, GT	–0.5	1.35	V
V_{CCT_GTBR}	Transmitter analog power supply for GT channels (right side)	GT	–0.5	1.35	V
V_{CCL_GTBR}	Transmitter clock network power supply (right side)	GT	–0.5	1.35	V
V_{CCH_GXBL}	Transmitter output buffer power supply (left side)	GX, GS, GT	–0.5	1.8	V
V_{CCH_GXBR}	Transmitter output buffer power supply (right side)	GX, GS, GT	–0.5	1.8	V

Maximum Allowed Overshoot and Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in Table 5 and undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 2 of 2)

Symbol	Description	Condition	Min *(4)*	Typ	Max *(4)*	Unit
t_{RAMP}	Power supply ramp time	Standard POR	200 µs	—	100 ms	—
		Fast POR	200 µs	—	4 ms	—

Notes to Table 6:

(1) V_{CCPD} must be 2.5 V when V_{CCIO} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCIO} is 3.0 V.

(2) If you do not use the design security feature in Stratix V devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Stratix V power-on-reset (POR) circuitry monitors V_{CCBAT}. Stratix V devices will not exit POR if V_{CCBAT} stays at logic low.

(3) C2L and I2L can also be run at 0.90 V for legacy boards that were designed for the C2 and I2 speed grades.

(4) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 7 lists the transceiver power supply recommended operating conditions for Stratix V GX, GS, and GT devices.

Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 1 of 2)

Symbol	Description	Devices	Minimum *(4)*	Typical	Maximum *(4)*	Unit
V_{CCA_GXBL} *(1), (3)*	Transceiver channel PLL power supply (left side)	GX, GS, GT	2.85	3.0	3.15	V
			2.375	2.5	2.625	
V_{CCA_GXBR} *(1), (3)*	Transceiver channel PLL power supply (right side)	GX, GS	2.85	3.0	3.15	V
			2.375	2.5	2.625	
V_{CCA_GTBR}	Transceiver channel PLL power supply (right side)	GT	2.85	3.0	3.15	V
V_{CCHIP_L}	Transceiver hard IP power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver hard IP power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHIP_R}	Transceiver hard IP power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver hard IP power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHSSI_L}	Transceiver PCS power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver PCS power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHSSI_R}	Transceiver PCS power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver PCS power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCR_GXBL} *(2)*	Receiver analog power supply (left side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±30	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±35	±35	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCPD} = 2.5 V	±25	±25	±25	±25	%

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices *(1), (2), (3), (4), (5), (6)*

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1:

(1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

(2) R_{SCAL} is the OCT resistance value at power-up.

(3) ΔT is the variation of temperature with respect to the temperature at power-up.

(4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.

(5) dR/dT is the percentage change of R_{SCAL} with temperature.

(6) dR/dV is the percentage change of R_{SCAL} with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) *(1)*

Symbol	Description	V_{CCIO} (V)	Typical	Unit
dR/dV	OCT variation with voltage without recalibration	3.0	0.0297	%/mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	

Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices *(1), (2)*

Symbol	Description	V_{CCIO} Conditions (V) *(3)*	Value *(4)*	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

Notes to Table 16:

(1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.

(2) The internal weak pull-down feature is only available for the JTAG `TCK` pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.

(3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

(4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V_{IH} and V_{IL}), output voltage (V_{OH} and V_{OL}), and current drive characteristics (I_{OH} and I_{OL}) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL}, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to "Glossary" on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012_486.

Table 17. Single-Ended I/O Standards for Stratix V Devices

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTL	2.85	3	3.15	–0.3	0.8	1.7	3.6	0.4	2.4	2	–2
LVCMOS	2.85	3	3.15	–0.3	0.8	1.7	3.6	0.2	V_{CCIO} – 0.2	0.1	–0.1
2.5 V	2.375	2.5	2.625	–0.3	0.7	1.7	3.6	0.4	2	1	–1
1.8 V	1.71	1.8	1.89	–0.3	0.35 * V_{CCIO}	0.65 * V_{CCIO}	V_{CCIO} + 0.3	0.45	V_{CCIO} – 0.45	2	–2
1.5 V	1.425	1.5	1.575	–0.3	0.35 * V_{CCIO}	0.65 * V_{CCIO}	V_{CCIO} + 0.3	0.25 * V_{CCIO}	0.75 * V_{CCIO}	2	–2
1.2 V	1.14	1.2	1.26	–0.3	0.35 * V_{CCIO}	0.65 * V_{CCIO}	V_{CCIO} + 0.3	0.25 * V_{CCIO}	0.75 * V_{CCIO}	2	–2

Table 18. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Stratix V Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	0.49 * V_{CCIO}	0.5 * VCCIO	0.51 * V_{CCIO}
SSTL-135 Class I, II	1.283	1.35	1.418	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}
SSTL-125 Class I, II	1.19	1.25	1.26	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	0.49 * V_{CCIO}	0.5 * VCCIO	0.51 * V_{CCIO}
SSTL-12 Class I, II	1.14	1.20	1.26	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	0.49 * V_{CCIO}	0.5 * VCCIO	0.51 * V_{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	—	V_{CCIO}/2	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.68	0.75	0.9	—	V_{CCIO}/2	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.47 * V_{CCIO}	0.5 * V_{CCIO}	0.53 * V_{CCIO}	—	V_{CCIO}/2	—
HSUL-12	1.14	1.2	1.3	0.49 * V_{CCIO}	0.5 * V_{CCIO}	0.51 * V_{CCIO}	—	—	—

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 1 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{ol} (mA)	I_{oh} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	–0.3	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} – 0.31	V_{REF} + 0.31	V_{TT} – 0.608	V_{TT} + 0.608	8.1	–8.1
SSTL-2 Class II	–0.3	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} – 0.31	V_{REF} + 0.31	V_{TT} – 0.81	V_{TT} + 0.81	16.2	–16.2
SSTL-18 Class I	–0.3	V_{REF} – 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} – 0.25	V_{REF} + 0.25	V_{TT} – 0.603	V_{TT} + 0.603	6.7	–6.7
SSTL-18 Class II	–0.3	V_{REF} – 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} – 0.25	V_{REF} + 0.25	0.28	V_{CCIO} – 0.28	13.4	–13.4
SSTL-15 Class I	—	V_{REF} – 0.1	V_{REF} + 0.1	—	V_{REF} – 0.175	V_{REF} + 0.175	0.2 * V_{CCIO}	0.8 * V_{CCIO}	8	–8
SSTL-15 Class II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	V_{REF} – 0.175	V_{REF} + 0.175	0.2 * V_{CCIO}	0.8 * V_{CCIO}	16	–16
SSTL-135 Class I, II	—	V_{REF} – 0.09	V_{REF} + 0.09	—	V_{REF} – 0.16	V_{REF} + 0.16	0.2 * V_{CCIO}	0.8 * V_{CCIO}	—	—
SSTL-125 Class I, II	—	V_{REF} – 0.85	V_{REF} + 0.85	—	V_{REF} – 0.15	V_{REF} + 0.15	0.2 * V_{CCIO}	0.8 * V_{CCIO}	—	—
SSTL-12 Class I, II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	V_{REF} – 0.15	V_{REF} + 0.15	0.2 * V_{CCIO}	0.8 * V_{CCIO}	—	—

Table 23. Transceiver Specifications for Stratix V GX and GS Devices *(1)* **(Part 5 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	2	—	—	2	—	—	2	—	dB
	DC Gain Setting = 2	—	4	—	—	4	—	—	4	—	dB
	DC Gain Setting = 3	—	6	—	—	6	—	—	6	—	dB
	DC Gain Setting = 4	—	8	—	—	8	—	—	8	—	dB
Transmitter											
Supported I/O Standards	—	1.4-V and 1.5-V PCML									
Data rate (Standard PCS)	—	600	—	12200	600	—	12200	600	—	8500/ 10312.5 *(24)*	Mbps
Data rate (10G PCS)	—	600	—	14100	600	—	12500	600	—	8500/ 10312.5 *(24)*	Mbps
Differential on-chip termination resistors	85-Ω setting	—	85 ± 20%	—	—	85 ± 20%	—	—	85 ± 20%	—	Ω
	100-Ω setting	—	100 ± 20%	—	—	100 ± 20%	—	—	100 ± 20%	—	Ω
	120-Ω setting	—	120 ± 20%	—	—	120 ± 20%	—	—	120 ± 20%	—	Ω
	150-Ω setting	—	150 ± 20%	—	—	150 ± 20%	—	—	150 ± 20%	—	Ω
V_{OCM} (AC coupled)	0.65-V setting	—	650	—	—	650	—	—	650	—	mV
V_{OCM} (DC coupled)	—	—	650	—	—	650	—	—	650	—	mV
Rise time *(7)*	20% to 80%	30	—	160	30	—	160	30	—	160	ps
Fall time *(7)*	80% to 20%	30	—	160	30	—	160	30	—	160	ps
Intra-differential pair skew	Tx V_{CM} = 0.5 V and slew rate of 15 ps	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block transmitter channel-to-channel skew	x6 PMA bonded mode	—	—	120	—	—	120	—	—	120	ps

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) *(1)*

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Reference Clock								
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL						
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS						
Input Reference Clock Frequency (CMU PLL) *(6)*	—	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) *(6)*	—	100	—	710	100	—	710	MHz
Rise time	20% to 80%	—	—	400	—	—	400	ps
Fall time	80% to 20%	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to –0.5	—	—	0 to –0.5	—	%
On-chip termination resistors *(19)*	—	—	100	—	—	100	—	Ω
Absolute V_{MAX} *(3)*	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	
Absolute V_{MIN}	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
V_{ICM} (AC coupled)	Dedicated reference clock pin	1050/1000 *(2)*			1050/1000 *(2)*			mV
	RX reference clock pin	1.0/0.9/0.85 *(22)*			1.0/0.9/0.85 *(22)*			V
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
t_{INCCJ} *(3), (4)*	Input clock cycle-to-cycle jitter ($f_{REF} \geq 100$ MHz)	—	—	0.15	UI (p-p)
	Input clock cycle-to-cycle jitter ($f_{REF} < 100$ MHz)	–750	—	+750	ps (p-p)
t_{OUTPJ_DC} *(5)*	Period Jitter for dedicated clock output ($f_{OUT} \geq$ 100 MHz)	—	—	175 *(1)*	ps (p-p)
	Period Jitter for dedicated clock output ($f_{OUT} <$ 100 MHz)	—	—	17.5 *(1)*	mUI (p-p)
t_{FOUTPJ_DC} *(5)*	Period Jitter for dedicated clock output in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	250 *(11)*, 175 *(12)*	ps (p-p)
	Period Jitter for dedicated clock output in fractional PLL ($f_{OUT} < 100$ MHz)	—	—	25 *(11)*, 17.5 *(12)*	mUI (p-p)
t_{OUTCCJ_DC} *(5)*	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{OUT} \geq 100$ MHz)	—	—	175	ps (p-p)
	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{OUT} < 100$ MHz)	—	—	17.5	mUI (p-p)
$t_{FOUTCCJ\_DC}$ *(5)*	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	250 *(11)*, 175 *(12)*	ps (p-p)
	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} < 100$ MHz)+	—	—	25 *(11)*, 17.5 *(12)*	mUI (p-p)
t_{OUTPJ_IO} *(5), (8)*	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
t_{FOUTPJ_IO} *(5), (8), (11)*	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	600 *(10)*	ps (p-p)
	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} < 100$ MHz)	—	—	60 *(10)*	mUI (p-p)
t_{OUTCCJ_IO} *(5), (8)*	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} < 100$ MHz)	—	—	60 *(10)*	mUI (p-p)
$t_{FOUTCCJ\_IO}$ *(5), (8), (11)*	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	600 *(10)*	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{CASC\_OUTPJ\_DC}$ *(5), (6)*	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} \geq 100$ MHz)	—	—	175	ps (p-p)
	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} < 100$ MHz)	—	—	17.5	mUI (p-p)
f_{DRIFT}	Frequency drift after PFDENA is disabled for a duration of 100 µs	—	—	±10	%
dK_{BIT}	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k_{VALUE}	Numerator of Fraction	128	8388608	2147483648	—

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

☞ The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices *(1), (2)* **(Part 1 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK_in} (input clock frequency) True Differential I/O Standards	Clock boost factor W = 1 to 40 *(4)*	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards *(3)*	Clock boost factor W = 1 to 40 *(4)*	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 *(4)*	5	—	520	5	—	520	5	—	420	5	—	420	MHz
f_{HSCLK_OUT} (output clock frequency)	—	5	—	800	5	—	800	5	—	625 *(5)*	5	—	525 *(5)*	MHz

Table 36. High-Speed I/O Specifications for Stratix V Devices *(1), (2)* **(Part 3 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t_{DUTY}	Transmitter output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	45	50	55	%
t_{RISE} & t_{FALL}	True Differential I/O Standards	—	—	160	—	—	160	—	—	200	—	—	200	ps
	Emulated Differential I/O Standards with three external output resistor networks	—	—	250	—	—	250	—	—	250	—	—	300	ps
TCCS	True Differential I/O Standards	—	—	150	—	—	150	—	—	150	—	—	150	ps
	Emulated Differential I/O Standards	—	—	300	—	—	300	—	—	300	—	—	300	ps
Receiver														
True Differential I/O Standards - $f_{HSDRDPA}$ (data rate)	SERDES factor J = 3 to 10 *(11), (12), (13), (14), (15), (16)*	150	—	1434	150	—	1434	150	—	1250	150	—	1050	Mbps
	SERDES factor J ≥ 4 LVDS RX with DPA *(12), (14), (15), (16)*	150	—	1600	150	—	1600	150	—	1600	150	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps
	SERDES factor J = 1, uses SDR Register	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps

Figure 7 shows the dynamic phase alignment (DPA) lock time specifications with the DPA PLL calibration option enabled.

Figure 7. DPA Lock Time Specification with DPA PLL Calibration Enabled

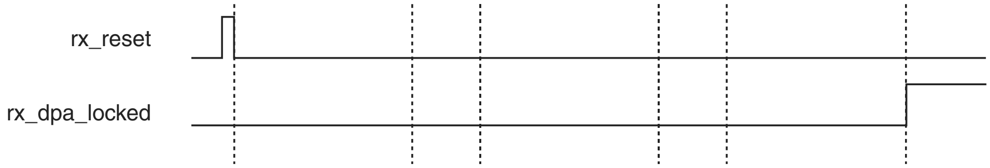


Table 37 lists the DPA lock time specifications for Stratix V devices.

Table 37. DPA Lock Time Specifications for Stratix V GX Devices Only *(1), (2), (3)*

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions *(4)*	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 37:

(1) The DPA lock time is for one channel.

(2) One data transition is defined as a 0-to-1 or 1-to-0 transition.

(3) The DPA lock time stated in this table applies to both commercial and industrial grade.

(4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 8 shows the **LVDS** soft-clock data recovery (CDR)/DPA sinusoidal jitter tolerance specification for a data rate ≥ 1.25 Gbps. Table 38 lists the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate ≥ 1.25 Gbps.

Figure 8. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate ≥ 1.25 Gbps

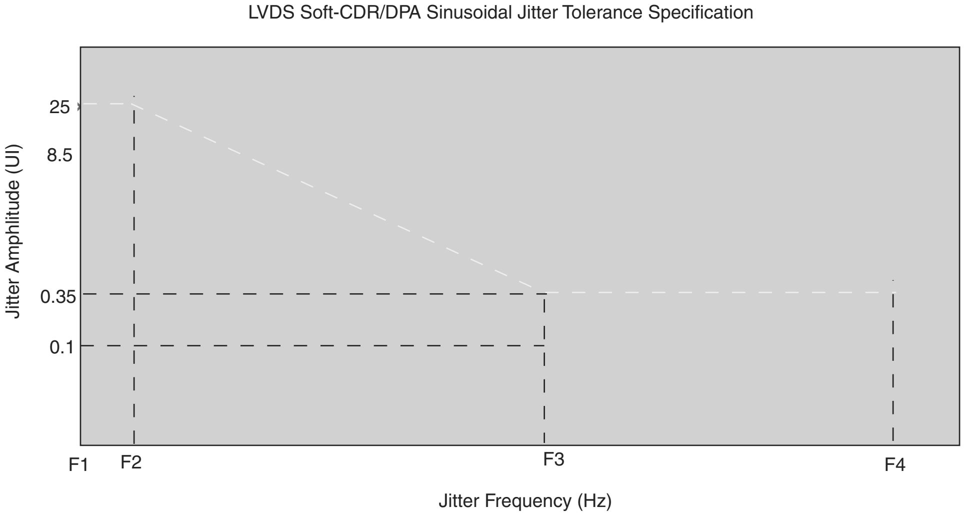


Table 48. Minimum Configuration Time Estimation for Stratix V Devices

Variant	Member Code	Active Serial (1)			Fast Passive Parallel (2)		
		Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
GS	D3	4	100	0.344	32	100	0.043
	D4	4	100	0.534	32	100	0.067
		4	100	0.344	32	100	0.043
	D5	4	100	0.534	32	100	0.067
	D6	4	100	0.741	32	100	0.093
	D8	4	100	0.741	32	100	0.093
E	E9	4	100	0.857	32	100	0.107
	EB	4	100	0.857	32	100	0.107

Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

Fast Passive Parallel Configuration Timing

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

DCLK-to-DATA[] Ratio for FPP Configuration

FPP configuration requires a different `DCLK`-to-`DATA[]` ratio when you enable the design security, decompression, or both features. Table 49 lists the `DCLK`-to-`DATA[]` ratio for each combination.

Table 49. DCLK-to-DATA[] Ratio (1) (Part 1 of 2)

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×8	Disabled	Disabled	1
	Disabled	Enabled	1
	Enabled	Disabled	2
	Enabled	Enabled	2
FPP ×16	Disabled	Disabled	1
	Disabled	Enabled	2
	Enabled	Disabled	4
	Enabled	Enabled	4

Table 49. DCLK-to-DATA[] Ratio *(1)* **(Part 2 of 2)**

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×32	Disabled	Disabled	1
	Disabled	Enabled	4
	Enabled	Disabled	8
	Enabled	Enabled	8

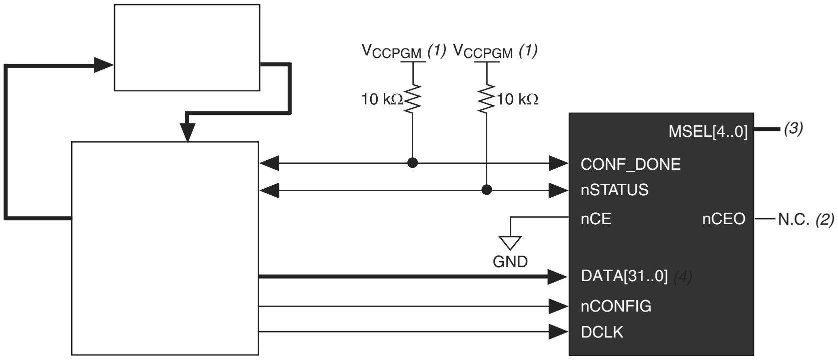
Note to Table 49:

(1) Depending on the `DCLK`-to-`DATA[]` ratio, the host must send a `DCLK` frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the `DCLK`-to-`DATA[]` ratio is 2, the `DCLK` frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.

If the `DCLK`-to-`DATA[]` ratio is greater than 1, at the end of configuration, you can only stop the `DCLK` (`DCLK`-to-`DATA[]` ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host



Notes to Figure 11:

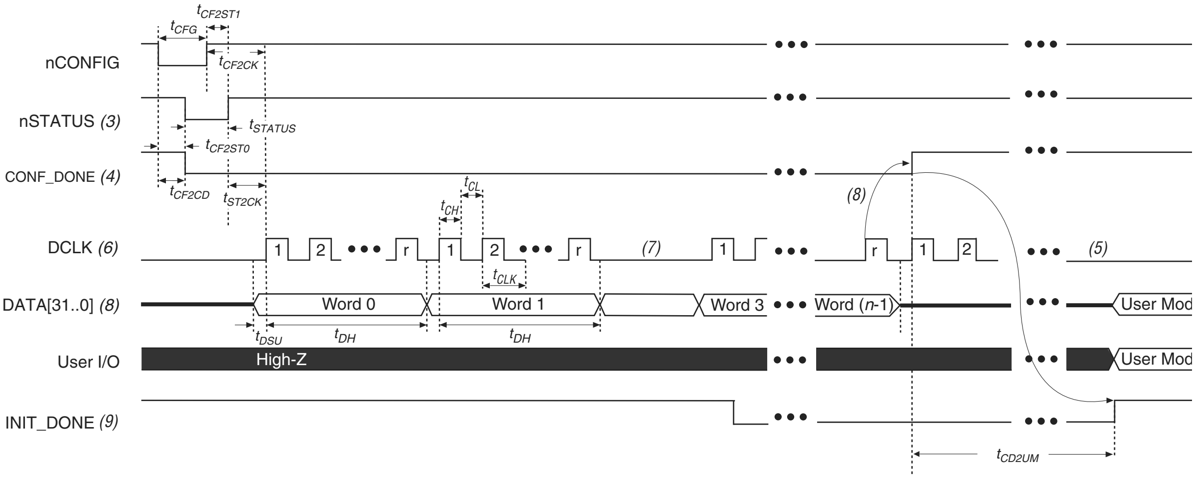
(1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM}.

(2) You can leave the `nCEO` pin unconnected or use it as a user I/O pin when it does not feed another device's `nCE` pin.

(3) The `MSEL` pin settings vary for different data width, configuration voltage standards, and POR delay. To connect `MSEL`, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

(4) If you use FPP ×8, use `DATA[7..0]`. If you use FPP ×16, use `DATA[15..0]`.

Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 *(1), (2)*



Notes to Figure 13:

(1) Use this timing waveform and parameters when the `DCLK`-to-`DATA[]` ratio is >1. To find out the `DCLK`-to-`DATA[]` ratio for your system, refer to Table 49 on page 55.

(2) The beginning of this waveform shows the device in user mode. In user mode, `nCONFIG`, `nSTATUS`, and `CONF_DONE` are at logic high levels. When `nCONFIG` is pulled low, a reconfiguration cycle begins.

(3) After power-up, the Stratix V device holds `nSTATUS` low for the time as specified by the POR delay.

(4) After power-up, before and during configuration, `CONF_DONE` is low.

(5) Do not leave `DCLK` floating after configuration. You can drive it high or low, whichever is more convenient.

(6) "r" denotes the `DCLK`-to-`DATA[]` ratio. For the `DCLK`-to-`DATA[]` ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.

(7) If needed, pause `DCLK` by holding it low. When `DCLK` restarts, the external host must provide data on the `DATA[31..0]` pins prior to sending the first `DCLK` rising edge.

(8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. `CONF_DONE` is released high after the Stratix V device receives all the configuration data successfully. After `CONF_DONE` goes high, send two additional falling edges on `DCLK` to begin initialization and enter user mode.

(9) After the option bit to enable the `INIT_DONE` pin is configured into the device, the `INIT_DONE` goes low.

Active Serial Configuration Timing

Table 52 lists the `DCLK` frequency specification in the AS configuration scheme.

Table 52. DCLK Frequency Specification in the AS Configuration Scheme *(1), (2)*

Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

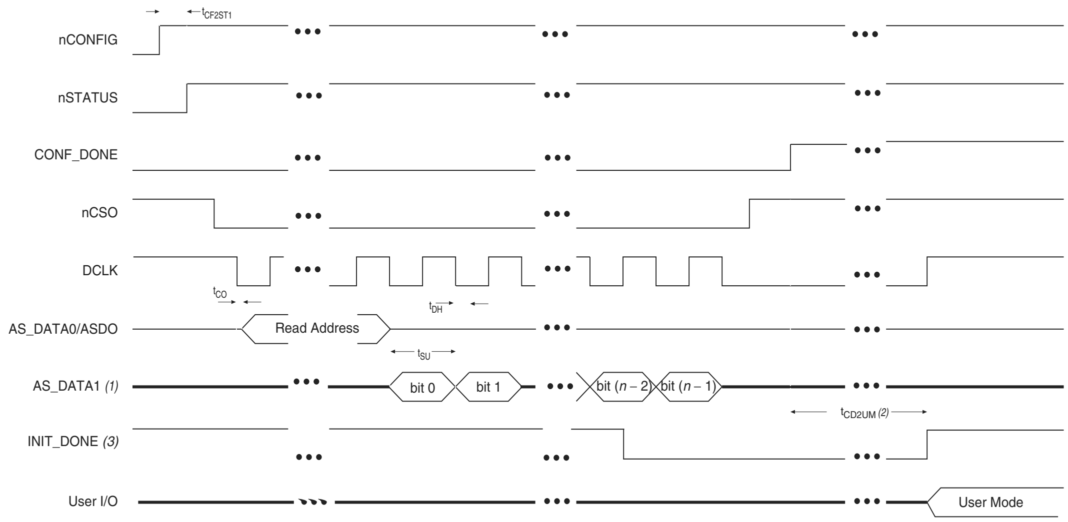
Notes to Table 52:

(1) This applies to the `DCLK` frequency specification when using the internal oscillator as the configuration clock source.

(2) The AS multi-device configuration scheme does not support `DCLK` frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.

Figure 14. AS Configuration Timing



Notes to Figure 14:

(1) If you are using AS ×4 mode, this signal represents the `AS_DATA[3..0]` and EPCQ sends in 4-bits of data for each `DCLK` cycle.

(2) The initialization clock can be from internal oscillator or `CLKUSR` pin.

(3) After the option bit to enable the `INIT_DONE` pin is configured into the device, the `INIT_DONE` goes low.

Table 53 lists the timing parameters for AS ×1 and AS ×4 configurations in Stratix V devices.

Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices *(1), (2)* **(Part 1 of 2)**

Symbol	Parameter	Minimum	Maximum	Units
t_{CO}	`DCLK` falling edge to `AS_DATA0/ASDO` output	—	2	ns
t_{SU}	Data setup time before falling edge on `DCLK`	1.5	—	ns
t_H	Data hold time after falling edge on `DCLK`	0	—	ns

Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices *(1), (2)* **(Part 2 of 2)**

Symbol	Parameter	Minimum	Maximum	Units
t_{CD2UM}	`CONF_DONE` high to user mode *(3)*	175	437	µs
t_{CD2CU}	`CONF_DONE` high to `CLKUSR` enabled	4 × maximum `DCLK` period	—	—
t_{CD2UMC}	`CONF_DONE` high to user mode with `CLKUSR` option on	t_{CD2CU} + (8576 × `CLKUSR` period)	—	—

Notes to Table 53:

(1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

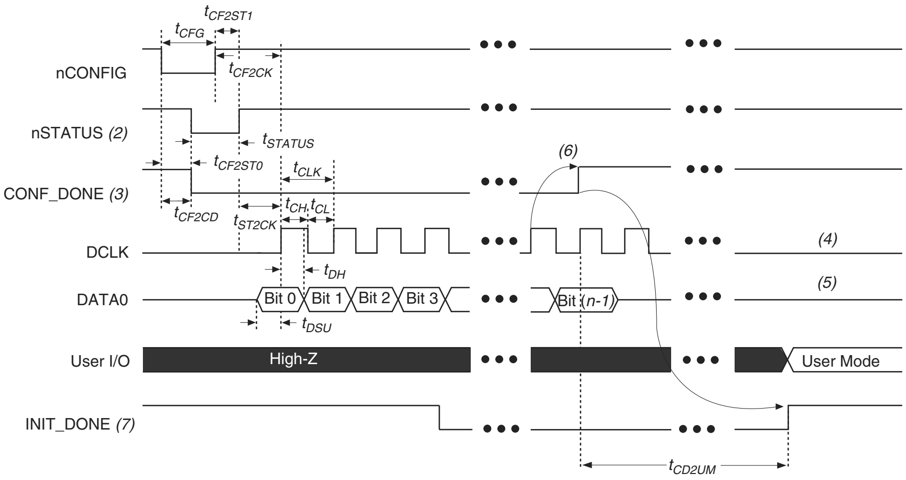
(2) t_{CF2CD}, t_{CF2ST0}, t_{CFG}, t_{STATUS}, and t_{CF2ST1} timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.

(3) To enable the `CLKUSR` pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

Passive Serial Configuration Timing

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform *(1)*



Notes to Figure 15:

(1) The beginning of this waveform shows the device in user mode. In user mode, `nCONFIG`, `nSTATUS`, and `CONF_DONE` are at logic high levels. When `nCONFIG` is pulled low, a reconfiguration cycle begins.

(2) After power-up, the Stratix V device holds `nSTATUS` low for the time of the POR delay.

(3) After power-up, before and during configuration, `CONF_DONE` is low.

(4) Do not leave `DCLK` floating after configuration. You can drive it high or low, whichever is more convenient.

(5) `DATA0` is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.

(6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. `CONF_DONE` is released high after the Stratix V device receives all the configuration data successfully. After `CONF_DONE` goes high, send two additional falling edges on `DCLK` to begin initialization and enter user mode.

(7) After the option bit to enable the `INIT_DONE` pin is configured into the device, the `INIT_DONE` goes low.

Table 60. Glossary (Part 4 of 4)

Letter	Subject	Definitions
V	$\mathbf{V}_{CM(DC)}$	DC common mode input voltage.
	$\mathbf{V}_{ICM}$	Input common mode voltage—The common mode of the differential signal at the receiver.
	$\mathbf{V}_{ID}$	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	$\mathbf{V}_{DIF(AC)}$	AC differential input voltage—Minimum AC input differential voltage required for switching.
	$\mathbf{V}_{DIF(DC)}$	DC differential input voltage— Minimum DC input differential voltage required for switching.
	$\mathbf{V}_{IH}$	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.
	$\mathbf{V}_{IH(AC)}$	High-level AC input voltage
	$\mathbf{V}_{IH(DC)}$	High-level DC input voltage
	$\mathbf{V}_{IL}$	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.
	$\mathbf{V}_{IL(AC)}$	Low-level AC input voltage
	$\mathbf{V}_{IL(DC)}$	Low-level DC input voltage
	$\mathbf{V}_{OCM}$	Output common mode voltage—The common mode of the differential signal at the transmitter.
	$\mathbf{V}_{OD}$	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.
	$\mathbf{V}_{SWING}$	Differential input voltage
	$\mathbf{V}_{X}$	Input differential cross point voltage
	$\mathbf{V}_{OX}$	Output differential cross point voltage
W	W	High-speed I/O block—clock boost factor
X Y Z	—	—

Document Revision History

Table 61 lists the revision history for this chapter.

Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes
June 2018	3.9	■ Added the “Stratix V Device Overshoot Duration” figure.
April 2017	3.8	■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table. ■ Changed the minimum value for t_{CD2UMC} in the “PS Timing Parameters for Stratix V Devices” table. ■ Changed the condition for 100-Ω R_D in the “OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices” table. ■ Changed the minimum value for t_{CD2UMC} in the “AS Timing Parameters for AS ´1 and AS ´4 Configurations in Stratix V Devices” table ■ Changed the minimum value for t_{CD2UMC} in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1” table. ■ Changed the minimum value for t_{CD2UMC} in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1” table. ■ Changed the minimum number of clock cycles value in the “Initialization Clock Source Option and the Maximum Frequency” table.
June 2016	3.7	■ Added the V_{ID} minimum specification for LVPECL in the “Differential I/O Standard Specifications for Stratix V Devices” table ■ Added the I_{OUT} specification to the “Absolute Maximum Ratings for Stratix V Devices” table.
December 2015	3.6	■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table.
December 2015	3.5	■ Changed the transmitter, receiver, and ATX PLL data rate specifications in the “Transceiver Specifications for Stratix V GX and GS Devices” table. ■ Changed the configuration .rbf sizes in the “Uncompressed .rbf Sizes for Stratix V Devices” table.

July 2015	3.4	■ Changed the data rate specification for transceiver speed grade 3 in the following tables:
		  ■ “Transceiver Specifications for Stratix V GX and GS Devices”
		  ■ “Stratix V Standard PCS Approximate Maximum Date Rate”
		  ■ “Stratix V 10G PCS Approximate Maximum Data Rate”
		■ Changed the conditions for reference clock rise and fall time, and added a note to the “Transceiver Specifications for Stratix V GX and GS Devices” table.
		■ Added a note to the “Minimum differential eye opening at receiver serial input pins” specification in the “Transceiver Specifications for Stratix V GX and GS Devices” table.
		■ Changed the t_{CO} maximum value in the “AS Timing Parameters for AS ´1 and AS ´4 Configurations in Stratix V Devices” table.
		■ Removed the CDR ppm tolerance specification from the “Transceiver Specifications for Stratix V GX and GS Devices” table.

Table 61. Document Revision History (Part 2 of 3)

Date	Version	Changes
November 2014	3.3	■ Added the I3YY speed grade and changed the data rates for the GX channel in Table 1. ■ Added the I3YY speed grade to the V_{CC} description in Table 6. ■ Added the I3YY speed grade to V_{CCHIP_L}, V_{CCHIP_R}, V_{CCHSSI_L}, and V_{CCHSSI_R} descriptions in Table 7. ■ Added 240-Ω to Table 11. ■ Changed CDR PPM tolerance in Table 23. ■ Added additional max data rate for fPLL in Table 23. ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25. ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26. ■ Changed CDR PPM tolerance in Table 28. ■ Added additional max data rate for fPLL in Table 28. ■ Changed the mode descriptions for MLAB and M20K in Table 33. ■ Changed the Max value of f_{HSCLK_OUT} for the C2, C2L, I2, I2L speed grades in Table 36. ■ Changed the frequency ranges for C1 and C2 in Table 39. ■ Changed the **.rbf** file sizes for 5SGSD6 and 5SGSD8 in Table 47. ■ Added note about `nSTATUS` to Table 50, Table 51, Table 54. ■ Changed the available settings in Table 58. ■ Changed the note in “Periphery Performance”. ■ Updated the “I/O Standard Specifications” section. ■ Updated the “Raw Binary File Size” section. ■ Updated the receiver voltage input range in Table 22. ■ Updated the max frequency for the LVDS clock network in Table 36. ■ Updated the `DCLK` note to Figure 11. ■ Updated Table 23 VO_{CM} (DC Coupled) condition. ■ Updated Table 6 and Table 7. ■ Added the `DCLK` specification to Table 55. ■ Updated the notes for Table 47. ■ Updated the list of parameters for Table 56.
November 2013	3.2	■ Updated Table 28
November 2013	3.1	■ Updated Table 33
November 2013	3.0	■ Updated Table 23 and Table 28
October 2013	2.9	■ Updated the “Transceiver Characterization” section
October 2013	2.8	■ Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59 ■ Added Figure 1 and Figure 3 ■ Added the “Transceiver Characterization” section ■ Removed all “Preliminary” designations.